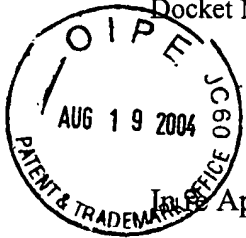


IFW

Docket No.: 87333.3341

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE



In Office Application of

Achim Melching, et al.

Serial No. 10/766,908

Filed: January 30, 2004

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: Group Art Unit: 3744
:
: Examiner:

For: CLIMATIC DEVICE, AND PROCESS FOR DEFROSTING A HEAT EXCHANGER
IN A CLIMATIC DEVICE

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

These references were cited in the International Search Report dated 6 July 2004. No further elaboration is believed necessary. Copies of the search report and cited art are submitted herewith in accordance with 37 C.F.R. 1.98(a).

AUTHORIZATION

No fee is required. The Commissioner is hereby authorized to charge any additional fees which may be required for this submission, or credit any overpayment to deposit account no. 50-2036.

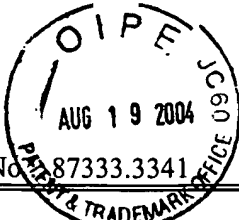
Respectfully submitted,

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Docket No. 87333.3341

PATENT

LIST OF ART CITED BY APPLICANT

(PTO-1449)

ATTY. DOCKET NO.
87333.3341SERIAL NO.
10/766,908APPLICANT
Achim Melching, et al.FILING DATE
January 30, 2004GROUP
2643

U.S. PATENT DOCUMENTS

	EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
A		4,572,283	2/25/86	Donald vanderschaaf	165	61	
B		6,146,267	11/14/00	Didier Beudon, et al.	454	188	
C		5,867,994	2/9/99	William L. Kopko	62	82	
D		4,479,431	12/25/90	Shizuo Fujimoto, et al.	98	6	
E							
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FOREIGN PATENT DOCUMENTS

	EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
U		2650686	11/5/76	DE			
V		3108678	3/7/81	DE			
W		141706	5/14/80	DE			
X							
Y							
Z							
AA							
BB							
CC							
DD							
EE							
FF							
GG							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

HH		
II		
JJ		
KK		
LL		
MM		
NN		

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.